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CONFIDENTIAL

1961

25X1

MEMORANDUM FOR: THE RECORD

SUBJECT : Trip Report

TIME & PLACE : 19-21 June 1961, [REDACTED], New York

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ATTENDANCE :

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1. The main purpose of this visit was to return and re-test previously received wire analyzers under contract number 237-1316-0. A secondary purpose was to familiarize [REDACTED] with the contractor's test procedures.

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2. The undersigned arrived in New York with the twelve (12) rejected analyzers on 19 June 1961.

3. The undersigned and [REDACTED] personnel re-tested the units on 20 June 1961 and conducted repairs where necessary. Attachment #1 describes the nature of the defects and repairs.

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4. It will be noted that practically all defects were the result of defective components. It was felt that defective components would be detected by the 100-Hour "burn-in" before test and shipment from the contractor. This, obviously, is not the case, since a few additional hours are resulting in numerous defective components.

5. The "burn-in" time on all remaining production units has been doubled to 200 Hours.

6. On 21 June 1961 the undersigned and [REDACTED] rechecked the returned twelve (12) units plus eleven (11) new units. Two of the new units exhibited the noisy transistor problem encountered on the rejects. (These new units had already received twenty (20) additional hours of "life" test.) All new units tested will be retained at the contractor's facility for an additional week of "life" tests.

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7. The twelve (12) re-tested units were returned to Washington on the night of 21 June 1961. [REDACTED] is to take care of all paper work concerning acceptance and disposition.

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Distribution:

Orig. -

1-P-227; 1-

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; 1-travel folder ; 1-chrono

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<u>SERIAL NUMBER</u>	<u>SYMPTOM</u>	<u>DEFECT</u>	<u>REPAIR</u>
235	Low Audio Amp. Gain	Faulty Transistor	Replace Transistor
238	Erratic Switch	No fault could be located.	
241	Low Oscillator Output	Faulty Transistor	Replace Transistor
244	Inoperative Oscillator	Faulty Transistor	Replace Transistor
246	Improper Charging Rate	Leaky Battery	Replace Battery
251	Steady VM Reading	Noisy Transistor	Replace Transistor
252	Steady VM Reading	Noisy Transistor	Replace Transistor
258	Steady VM Reading	Noisy Transistor	Replace Transistor
264	a. Erratic Oscillator	Faulty Transistor	Replace Transistor
	b. Steady Voltmeter Reading	Noisy Transistor	Replace Transistor
265	Inoperative Voltmeter on +DC/AUDIO	Faulty Rectifier	Replace Rectifier
266	Steady VM Reading	Noisy Transistor	Replace Transistor
267	Steady VM Reading	Noisy Transistor	Replace Transistor

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